

Silicon sensors for the AMS-L0 Upgrade: beam test setup and results

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Outline

1. AMS-02 experiment

Upgrade: layer 0 (L0)

2. Beam Test & Results

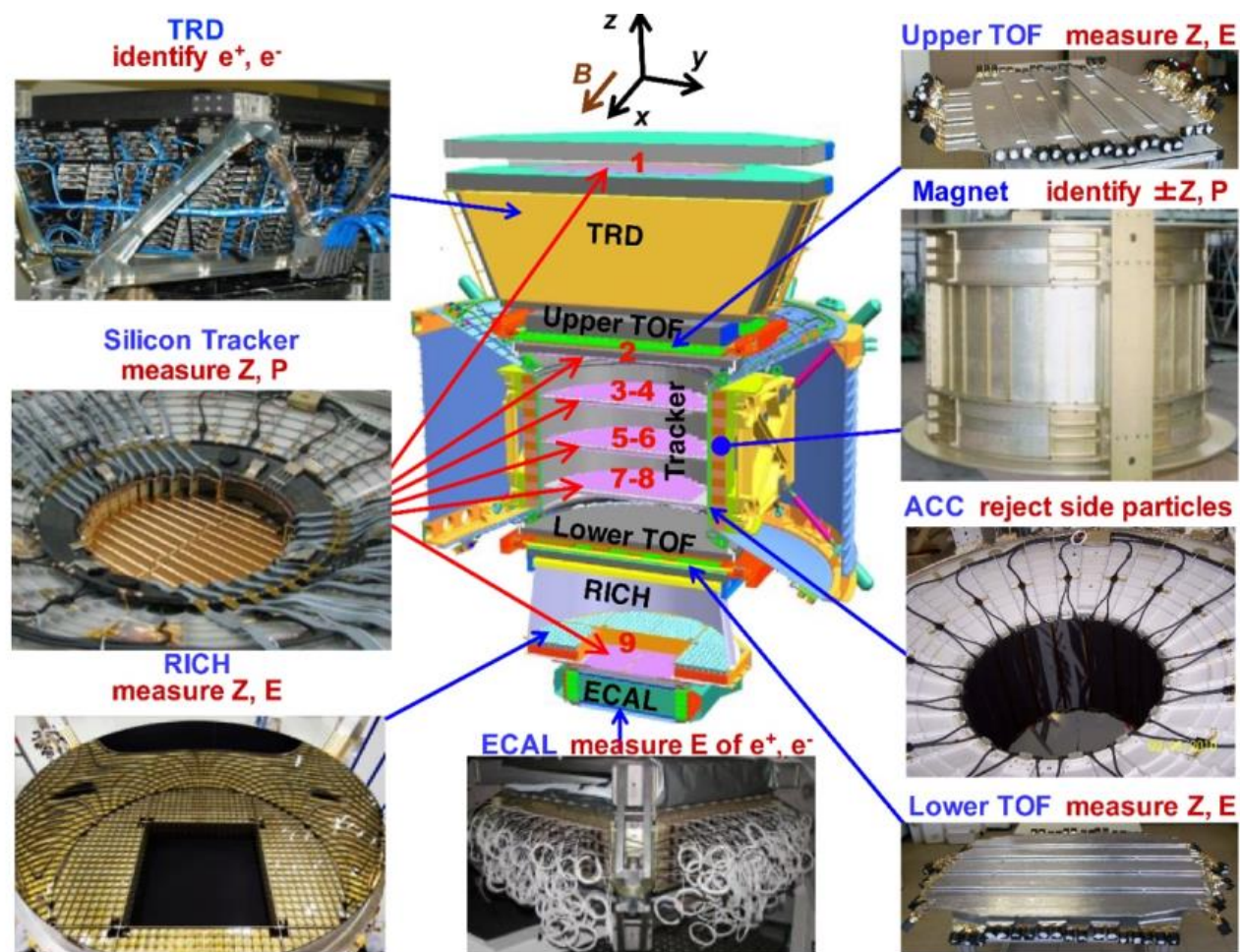
AMS 02: The Alpha Magnetic Spectrometer

Composed by:

- TRD (Transition Radiation Detector): distinguishes proton/antiproton from electron/positron
- TOF (Time of Flight): determines the particle time of flight and charge
- Tracker: measure the particle rigidity and charge
- RICH (Ring Imaging Cherenkov): measures the particle charge and velocity
- ECAL (Electromagnetic Calorimeter): distinguishes between proton/antiproton and electron/positron

Main objectives:

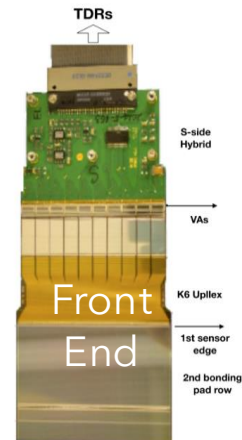
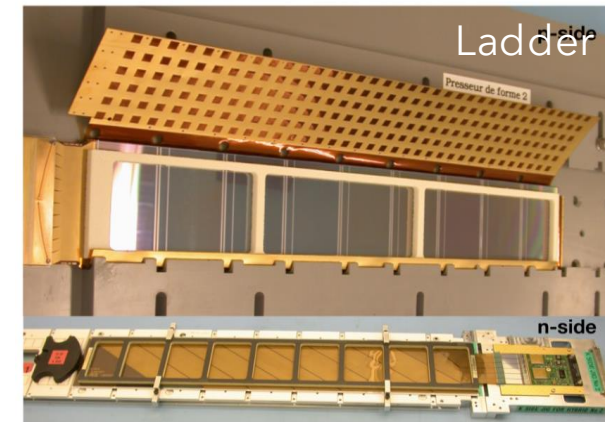
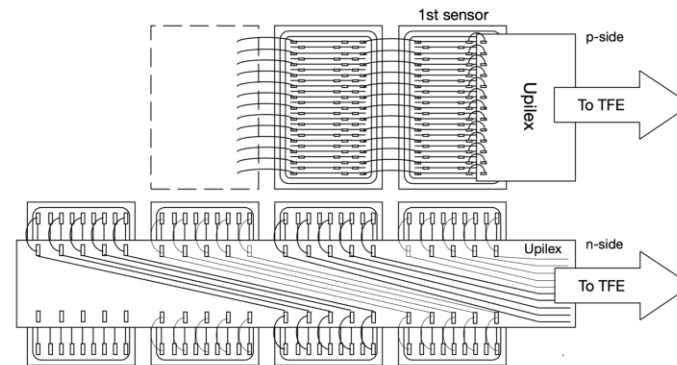
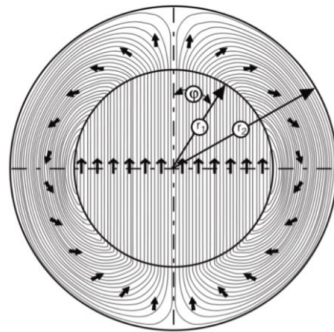
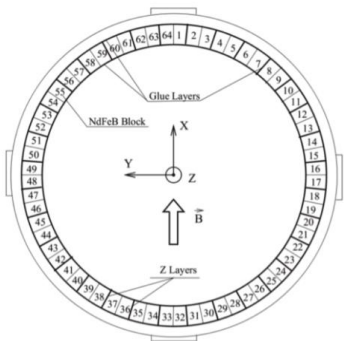
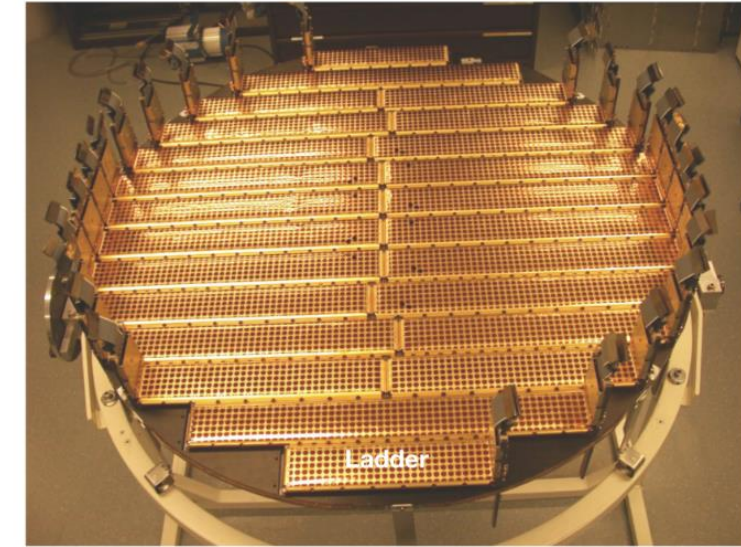
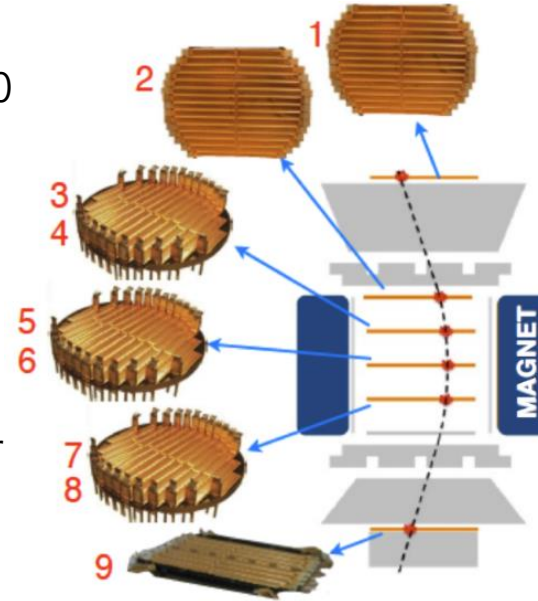
- search for Primordial Antimatter by direct detection of antinuclei
- search for indirect Dark Matter signals
- study of production, acceleration and propagation of Cosmic-Rays
- study of Solar Modulation



In orbit on the International Space Station since May 2011

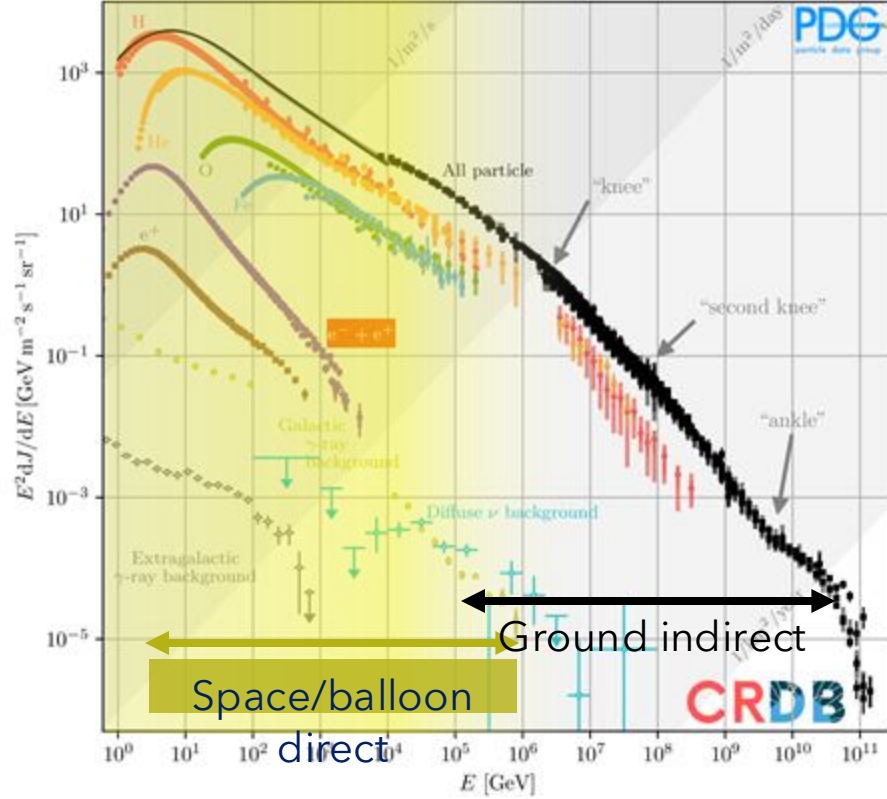
AMS 02: The magnetic spectrometer

- The magnetic field is generated by 64 sectors of Nd-Fe-B magnets in a Hallbach array configuration (1400 Gauss in the central region)
- Charged particle trajectories are influenced by the Lorentz force, leading to deflection
- The tracker consists of 9 layers of silicon microstrip detectors, each layer composed of 16-26 rectangular modules (*ladder*)
- Each ladder consists of 9 to 15 double-sided silicon sensors. The p-side (measuring y) strips with a readout pitch of $110\ \mu\text{m}$, while the n-side strips (measuring x) with a readout pitch of $208\ \mu\text{m}$



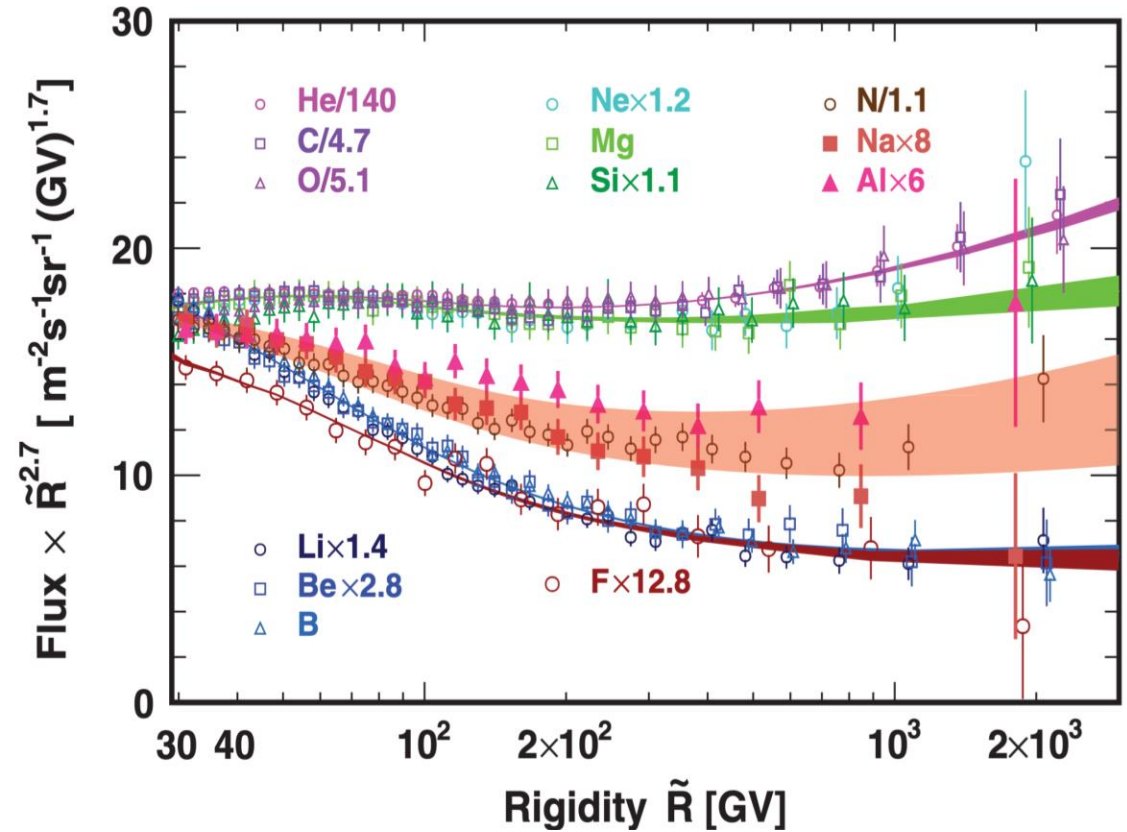
Magnet and Magnetic field

(Charged) Cosmic Rays



Spectrum:

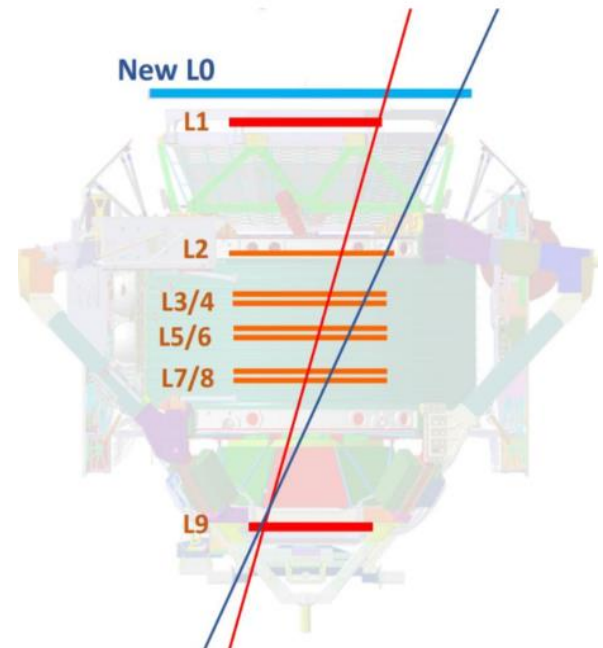
$$\Phi = \Phi_0 E^{-\gamma} \quad \text{with } \gamma \sim 3$$



- two classes of primaries:
 - light and very heavy (He, C, O, Fe, Ni)
 - heavy (Ne, Mg, Si, ...)
- mixed (N, Na, Al): primary + secondary with different composition

The AMS-02 Upgrade

- AMS02-L0, an upgrade which involves adding a new silicon detection layer, called L0, above the existing L1 layer to increase the overall acceptance area
- The total area of the silicon sensors to be installed is $\sim 8 \text{ m}^2$. Will increase by 300% the acceptance of the experiment
- Composed of two layers of silicon sensors, where one layer is measuring Y and the other is at 45°
- L0 will be installed in spring 2026

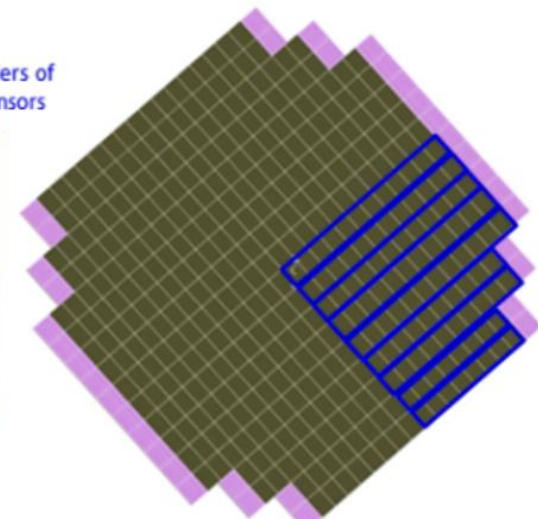
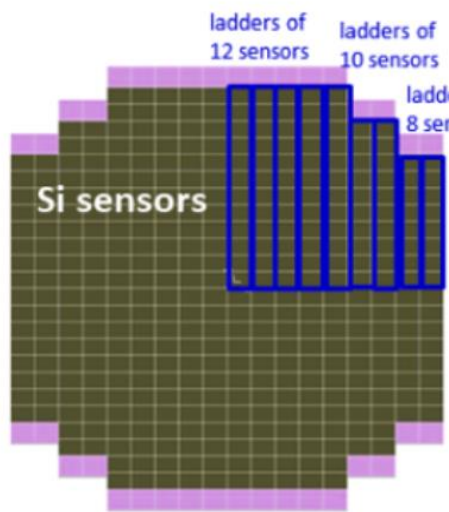
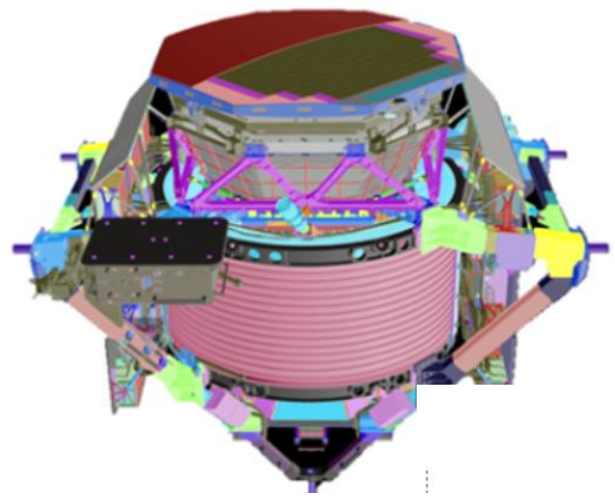


**New Silicon Tracker Layer:
One layer, two planes, each $\sim 4\text{m}^2$**

Acceptance increased to 300%

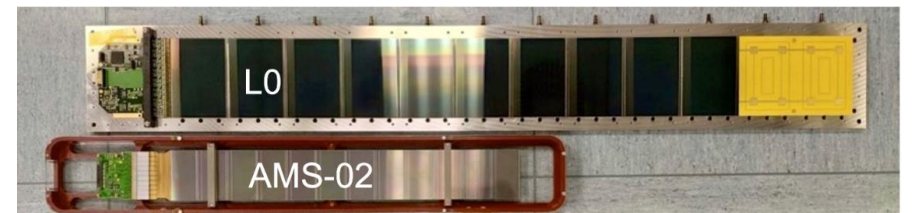
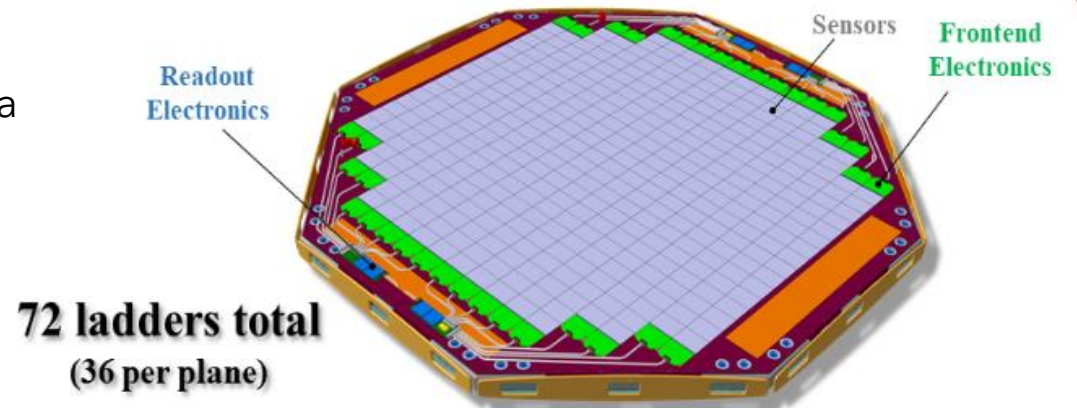
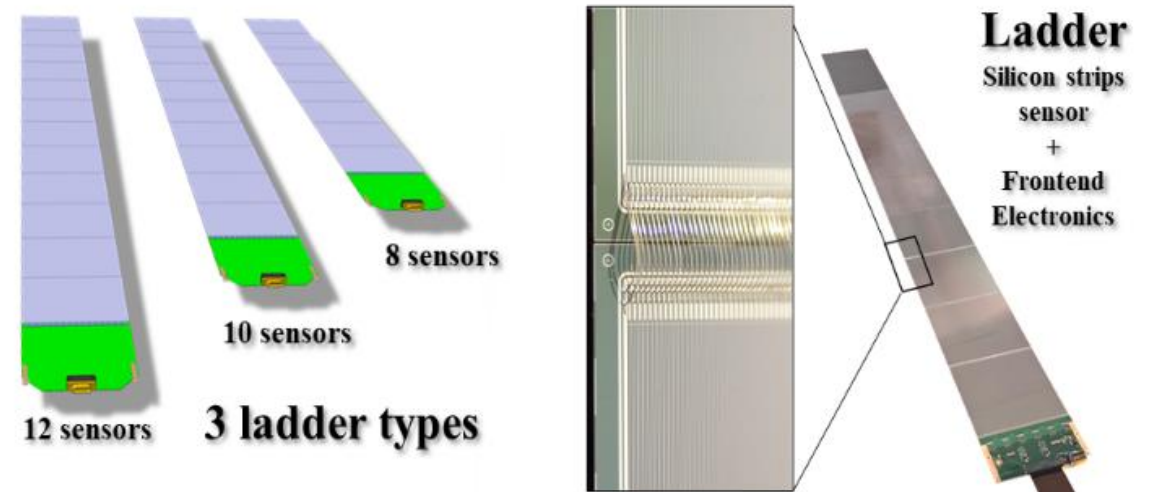
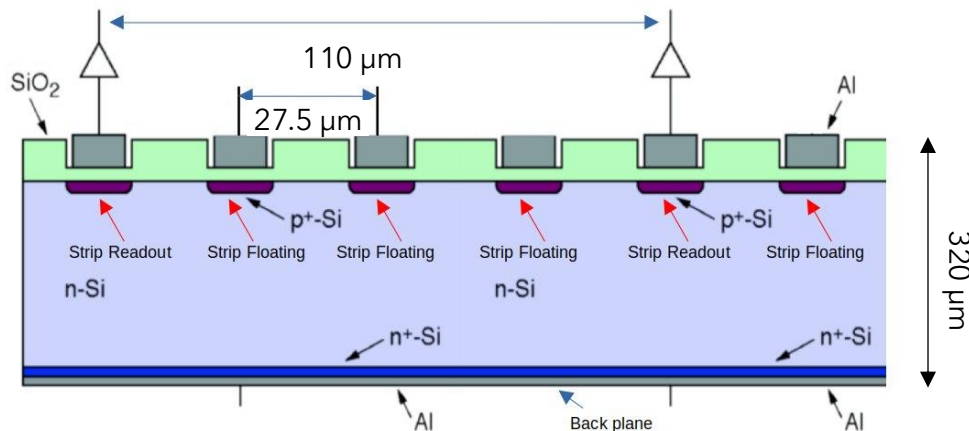
L0-Y
bending direction
7 micron

L0-U
rotated 45°
10 micron bending
10 micron non-bending



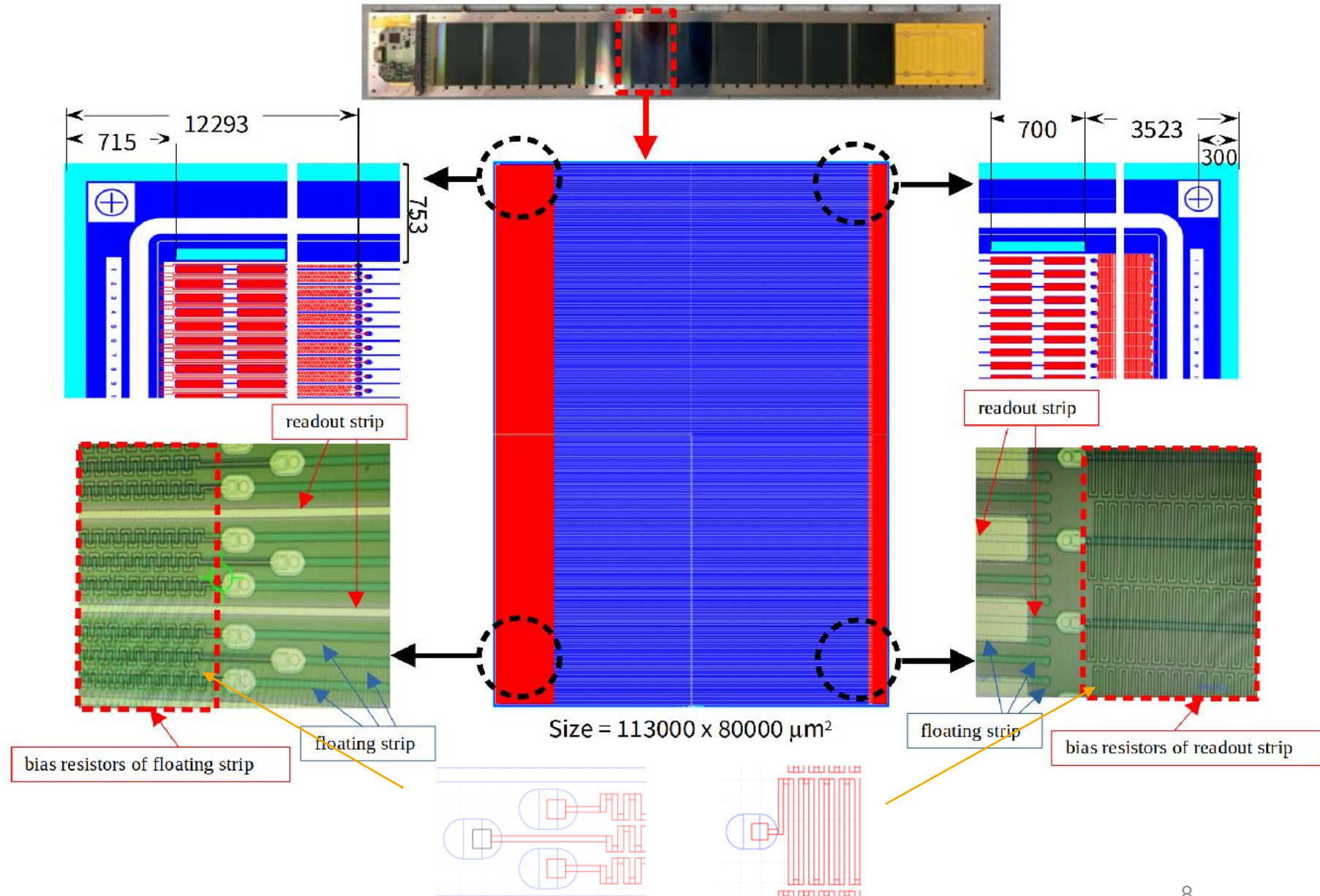
AMS-L0 Ladder

- Each silicon sensors has an area of $8 \times 11 \text{ cm}^2$, 1024 readout channels ($110 \mu\text{m}$ pitch)
- To cover large areas without increasing the number of channels. the design must be based on "long" silicon sensor modules (called *ladders*)
- All channels of adjacent silicon sensors are connected in daisy chain to form a single sensor with longer strips
- Each ladder is composed of 8, 10, or 12 silicon sensors plus a frontend electronics board and a long flexible printed circuit board for mounting



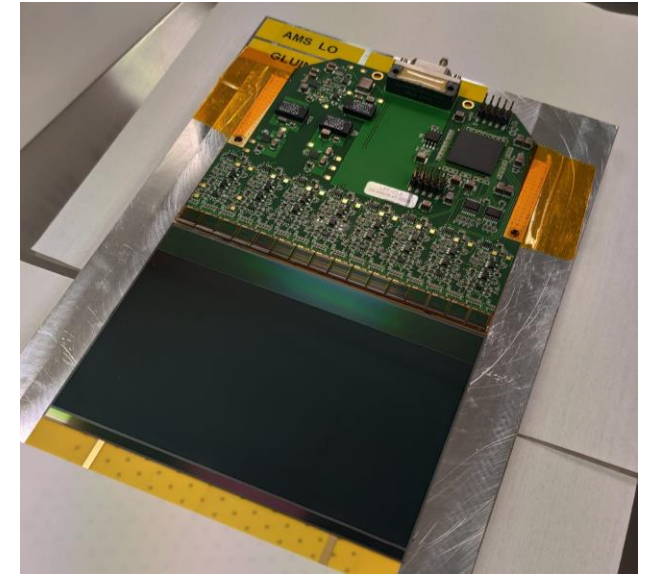
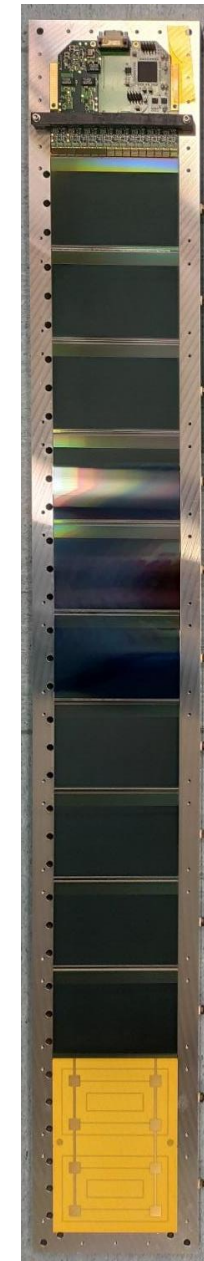
AMS-L0: resistor regions

- Bias resistors (polysilicon serpentines) to connect bias ring to each strip
 - needed for proper depletion voltage
- Bias resistors
 - readout strips: right end
 - intermediate (floating) strips: left end.
- Different sizes and structures for the two bias resistor regions
 - different efficiencies
 - different spatial resolutions



Beam tests:

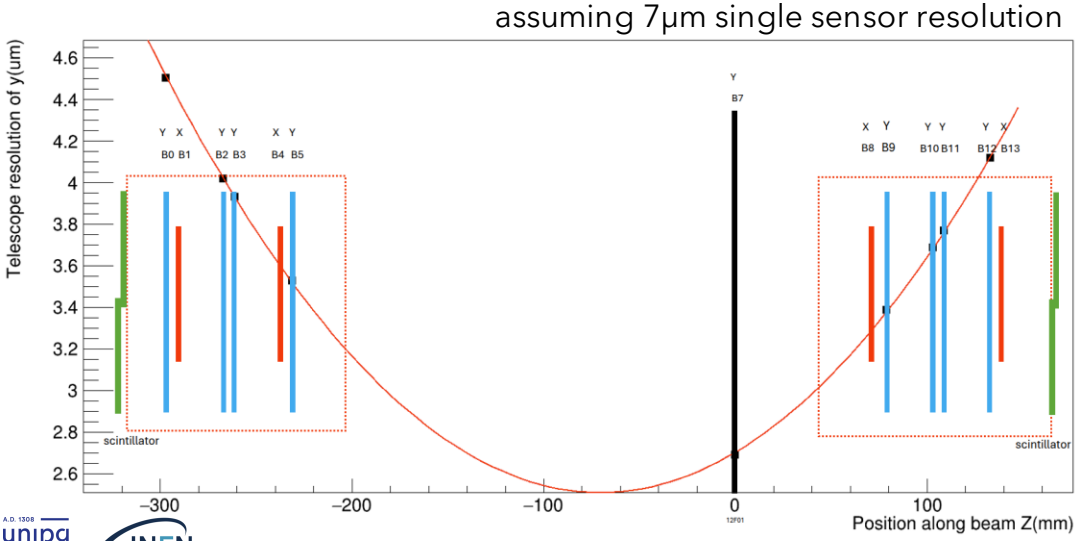
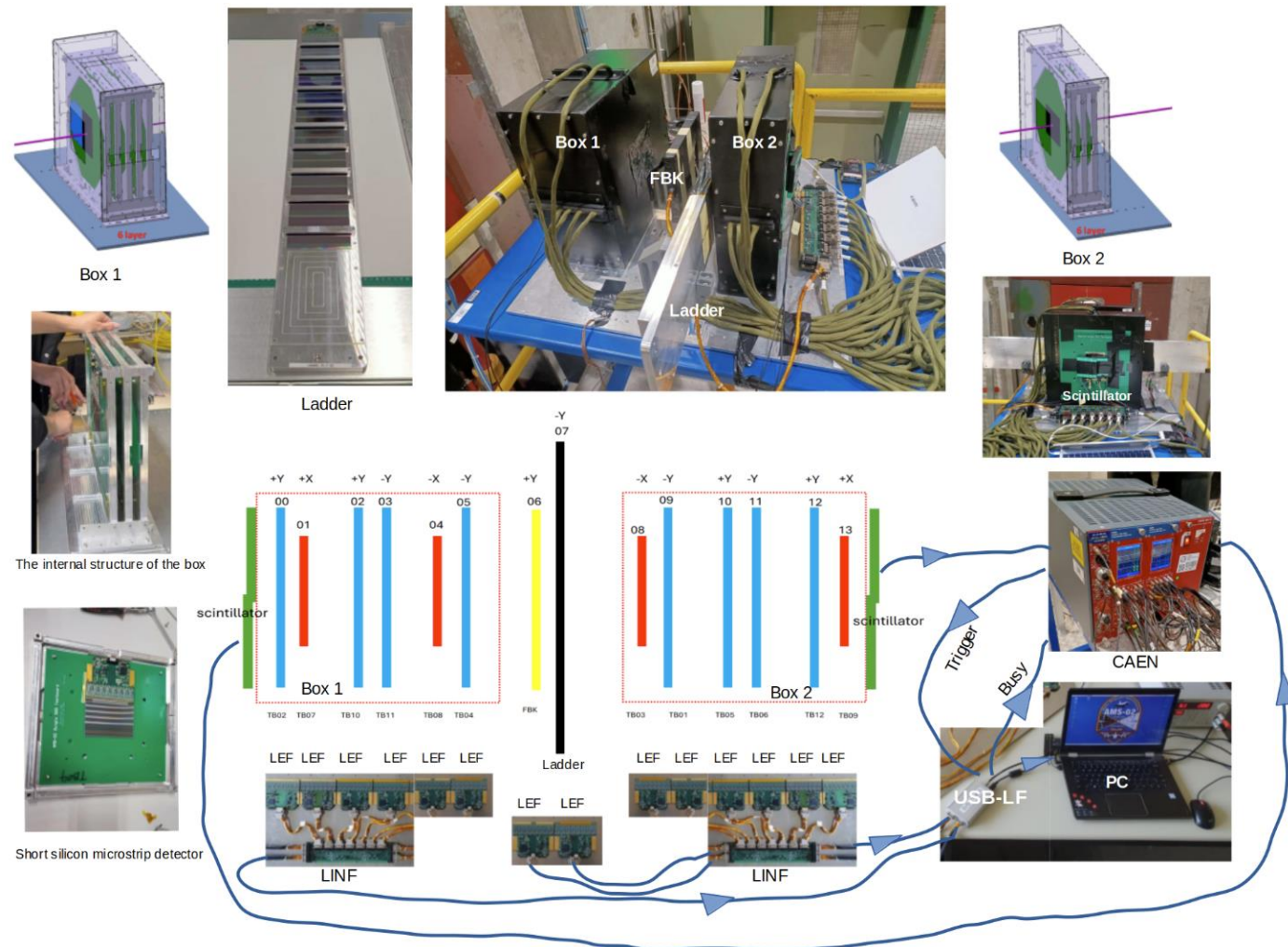
- S/N performance, spatial resolution, detection efficiency ($Z=1$)
 - muon (May 2024)
- Charge identification capability ($Z \gg 1$)
 - heavy ions (October 2023)
- The cross-section of the L0 structure on the incident particle
 - heavy ions (November 2024)



AMS-L0: single sensor detector (*Beam Monitor*) and Flight Ladder prototype

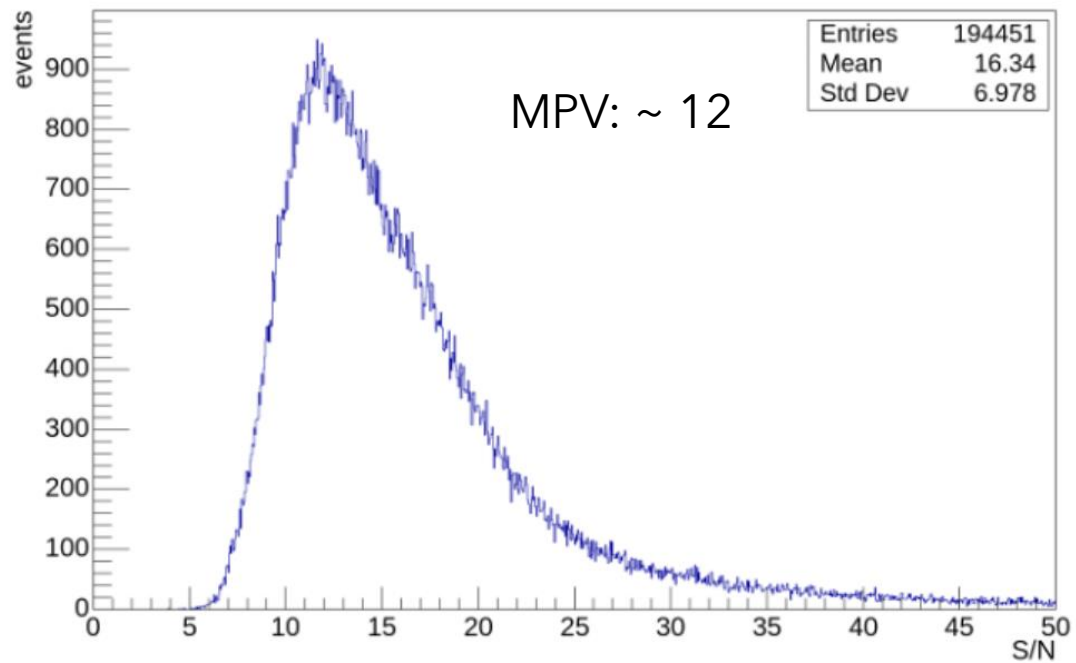
AMS-L0 muon beam test: setup

- Coincidence of two scintillators (green rectangles): trigger
- flight ladder (10 sensors) prototype under test
- short detectors (BM): ladders with 1 single silicon sensor, but functionally identical to flight ladder (same silicon sensors, same front-end)
- 12 short silicon microstrip detectors (red or blue rectangles) in two boxes: Beam Monitor and tracking system for spatial resolution of the flight ladder under test

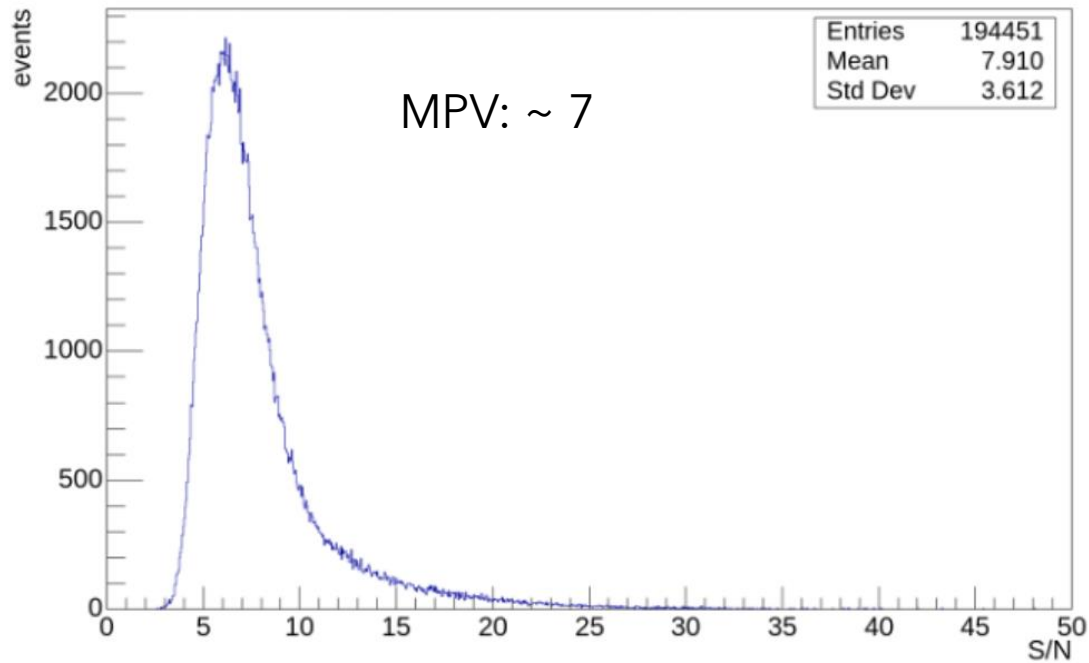


$$\sigma_{fit,i} = \sigma_s \sqrt{\left(\sum_j^n z_j^2/n + \cdot z_i^2 - 2z_i \cdot \sum_j^n z_j^2/n \right) / \left(\sum_j^n z_j^2 - \sum_j^n z_j \sum_k^n z_k \right)}$$

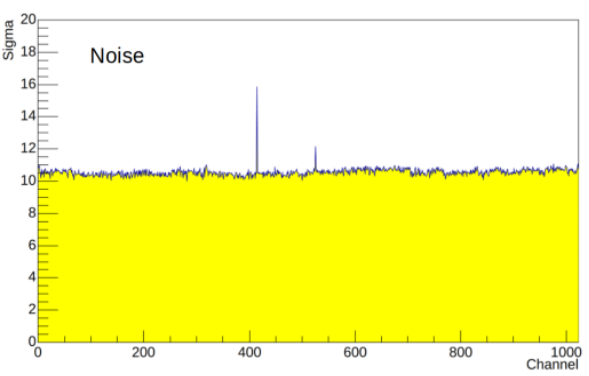
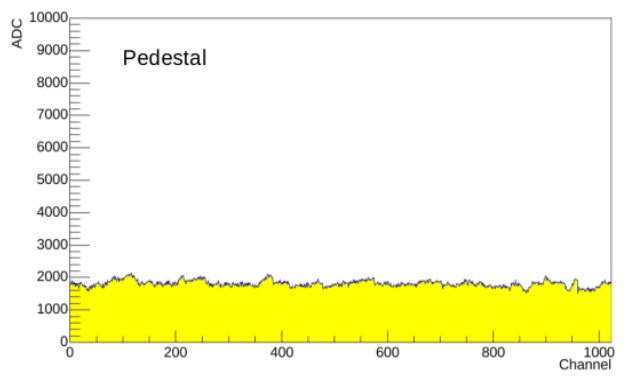
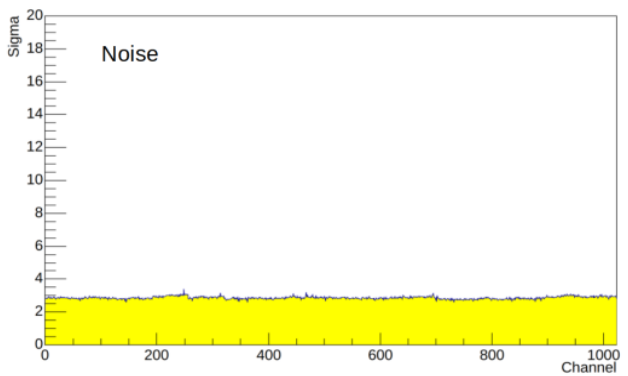
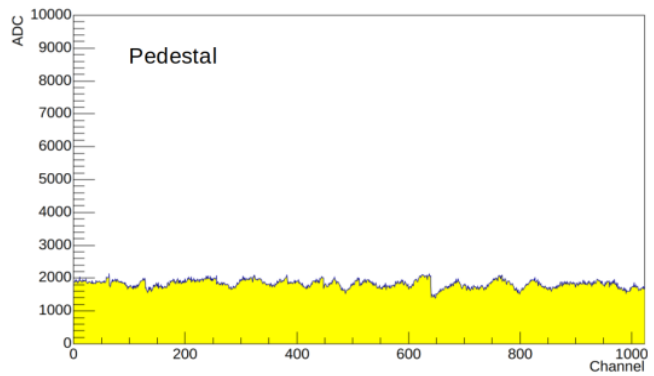
AMS-L0 muon beam test: calibration & S/N performance



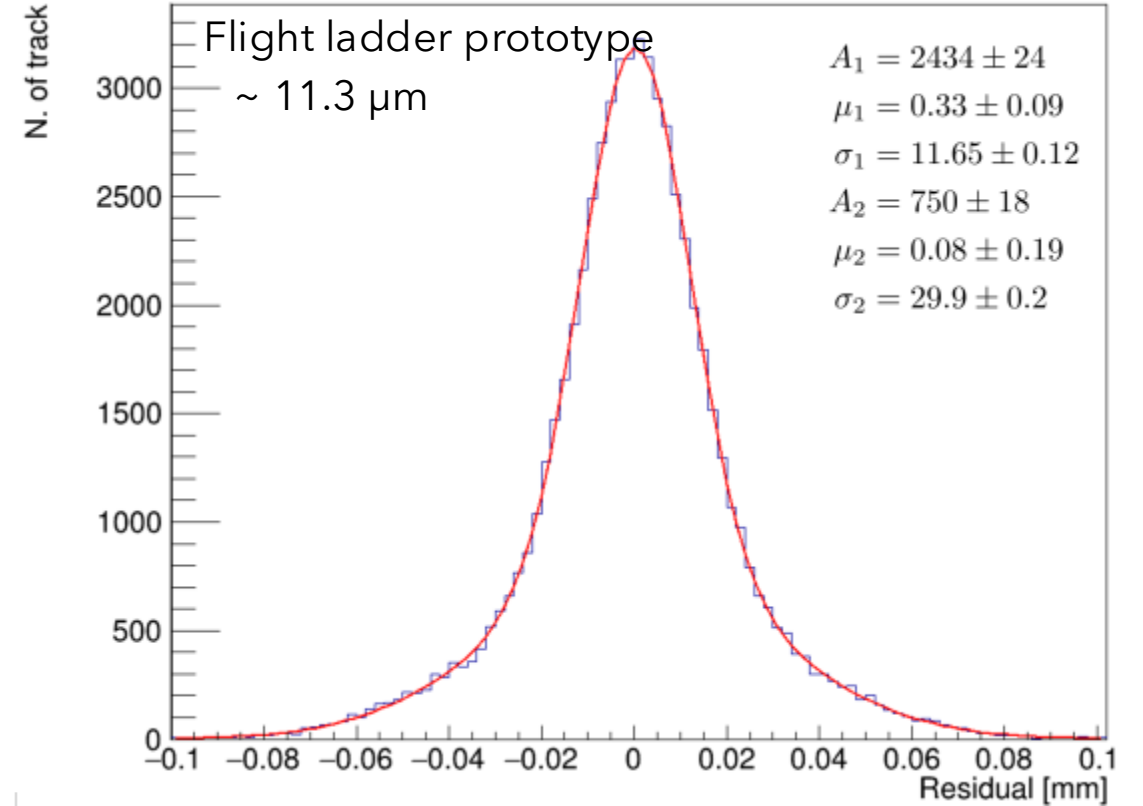
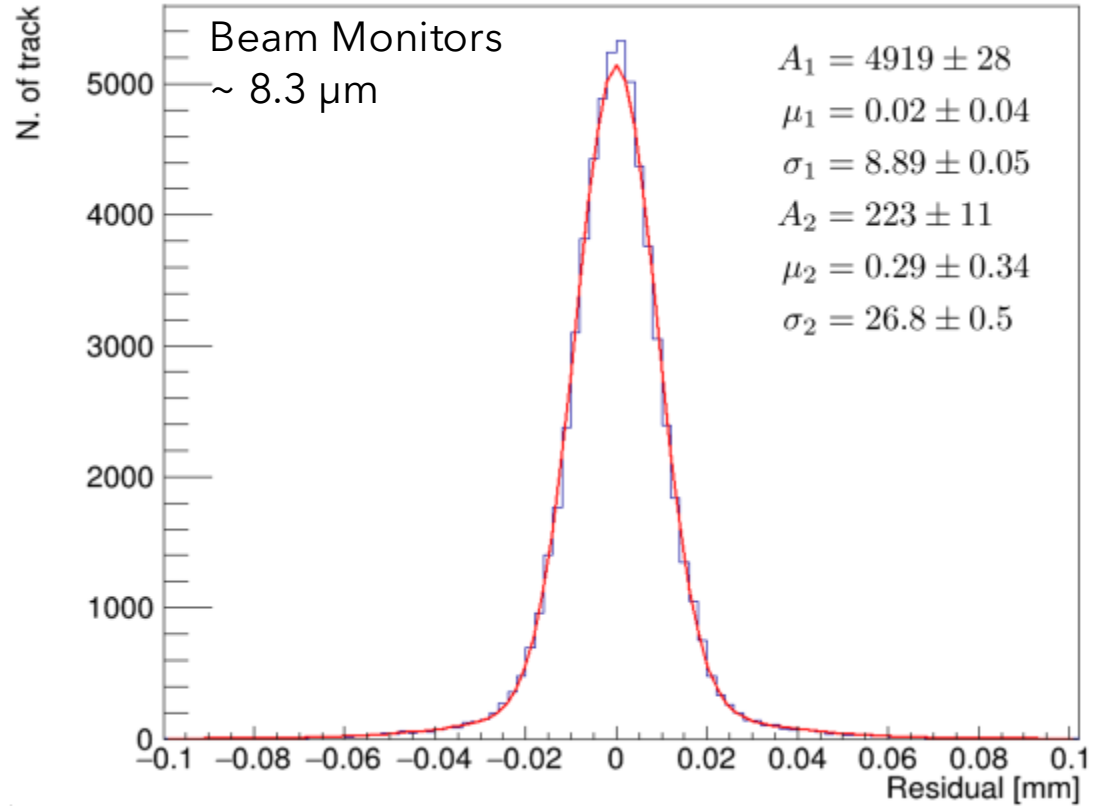
Beam Monitors



Flight ladder prototype



AMS-L0 muon beam test: spatial resolution



Unbiased residuals, fitted the sum of two Gaussian

Residual unbiased:

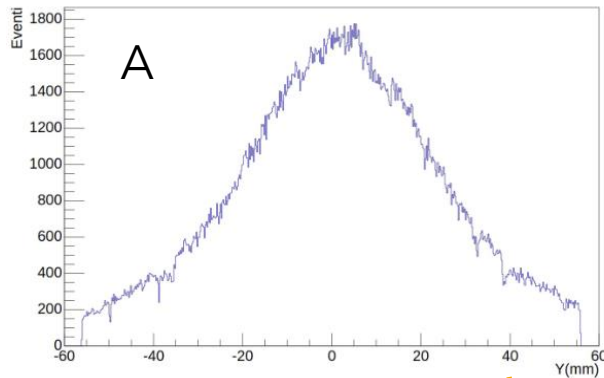
$$UR_i = X_{impact,i} - X_{predicted,i}$$

Standard deviation:

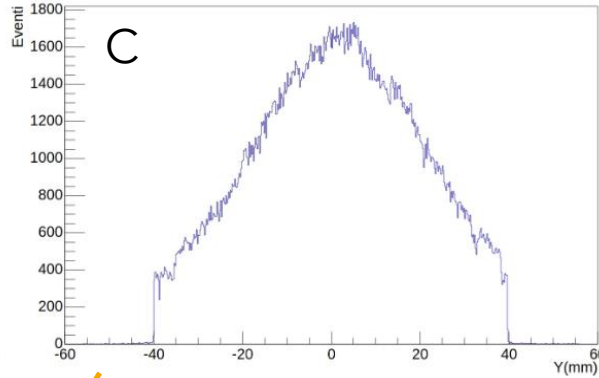
$$\sigma_{UR,i} = \sqrt{\sigma_{fit,i}^2 + \sigma_{resolution,i}^2}$$

$$\sigma_{fit,i} = \sigma_s \sqrt{\left(\sum_j^n z_j^2 / n + \cdot z_i^2 - 2z_i \cdot \sum_j^n z_j^2 / n \right) / \left(\sum_j^n z_j^2 - \sum_j^n z_j \sum_k^n z_k \right)}$$

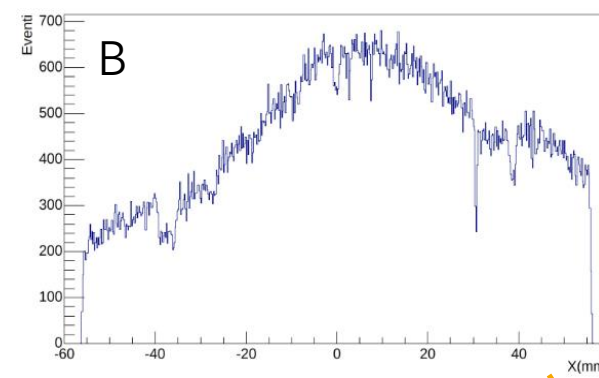
AMS-L0 muon beam test: detection efficiency in bias resistor regions



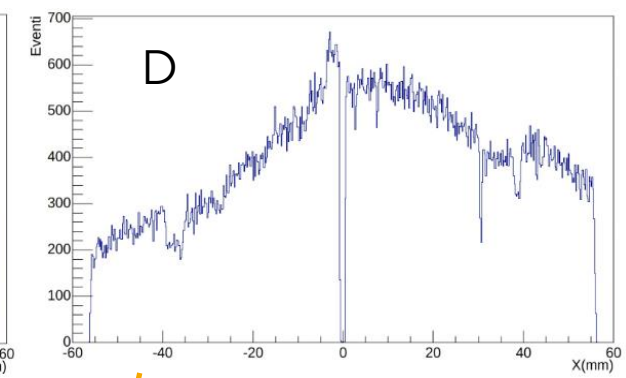
Beam position @ BM sensor location



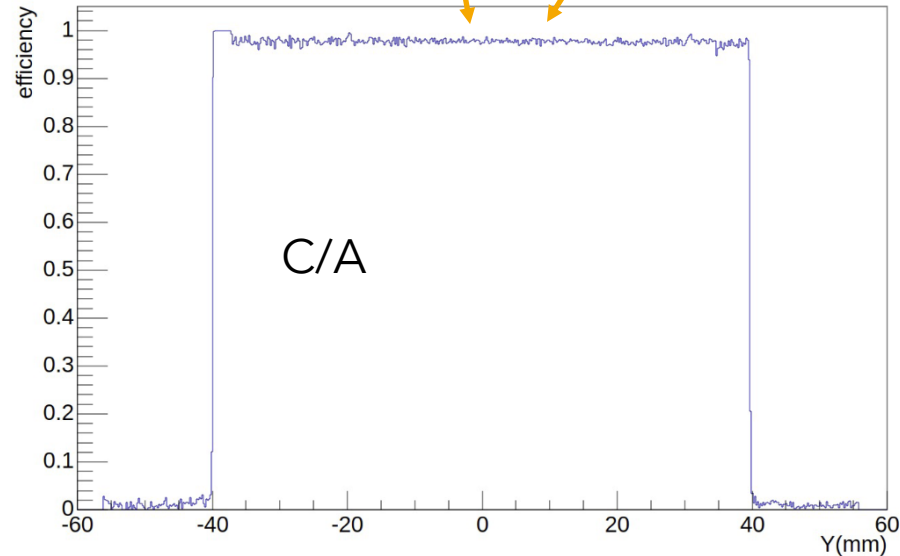
Beam position @ BM sensor & cluster in BM



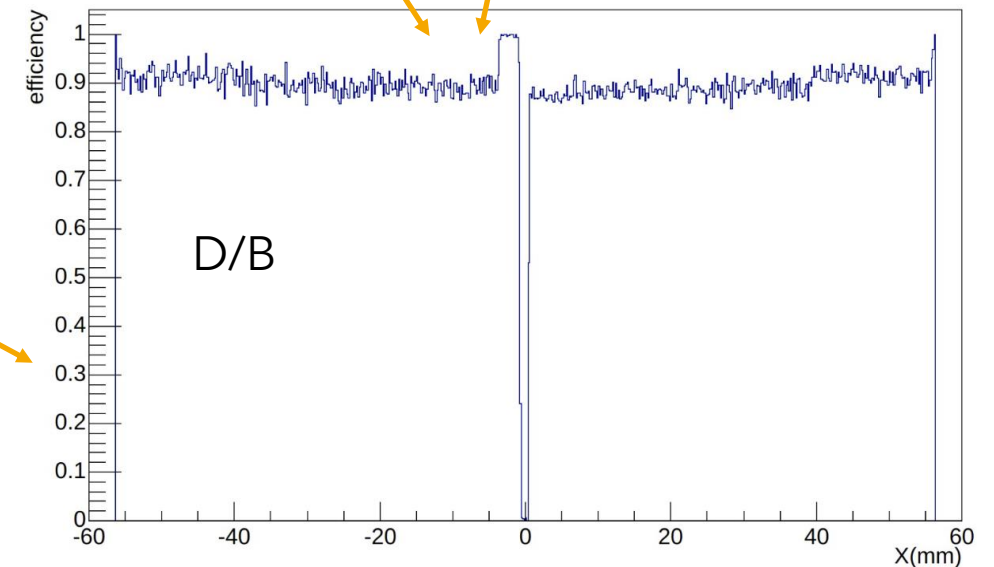
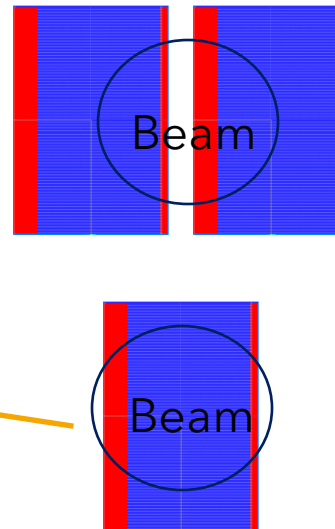
Beam position @ ladder location



Beam position @ ladder & cluster in ladder

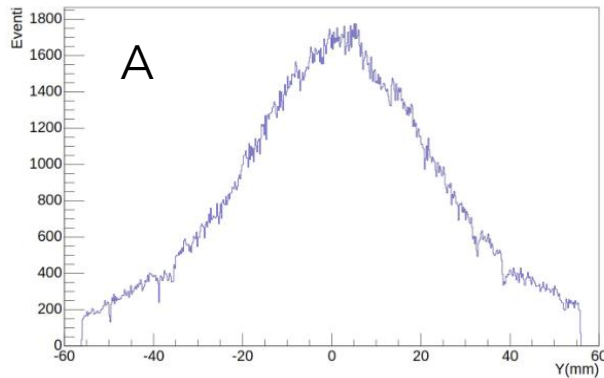


BM: detection efficiency as a function of the coordinate along the strip

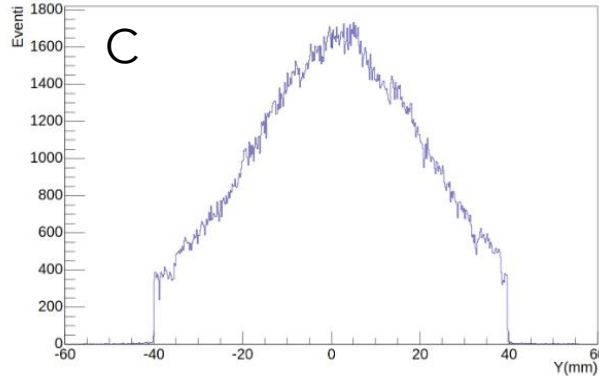


Flight ladder: detection efficiency as a function of the coordinate along the strips

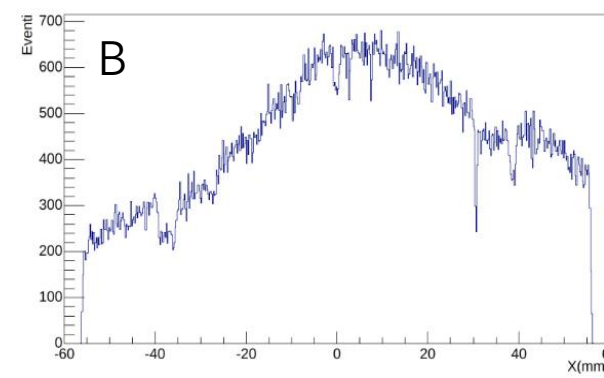
AMS-L0 muon beam test: detection efficiency in bias resistor regions



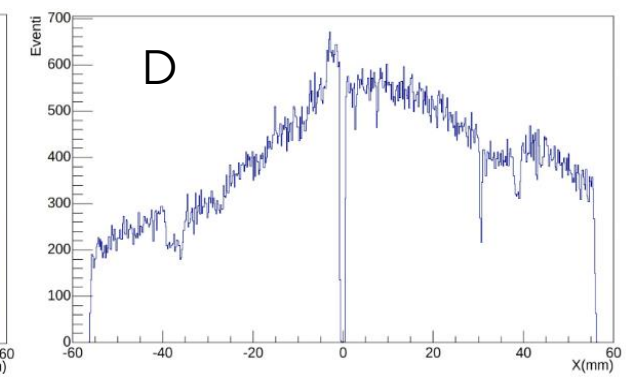
Beam position @ BM sensor location



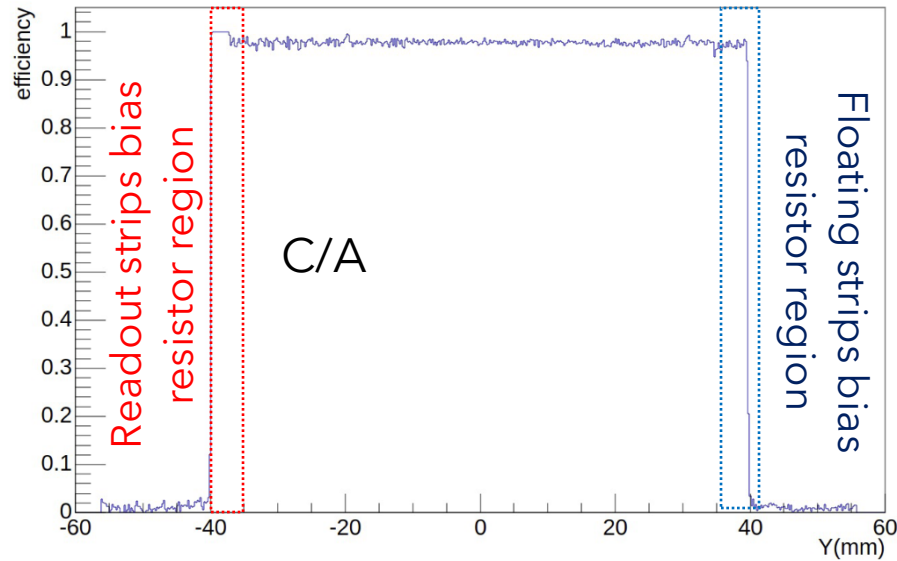
Beam position @ BM sensor & cluster in BM



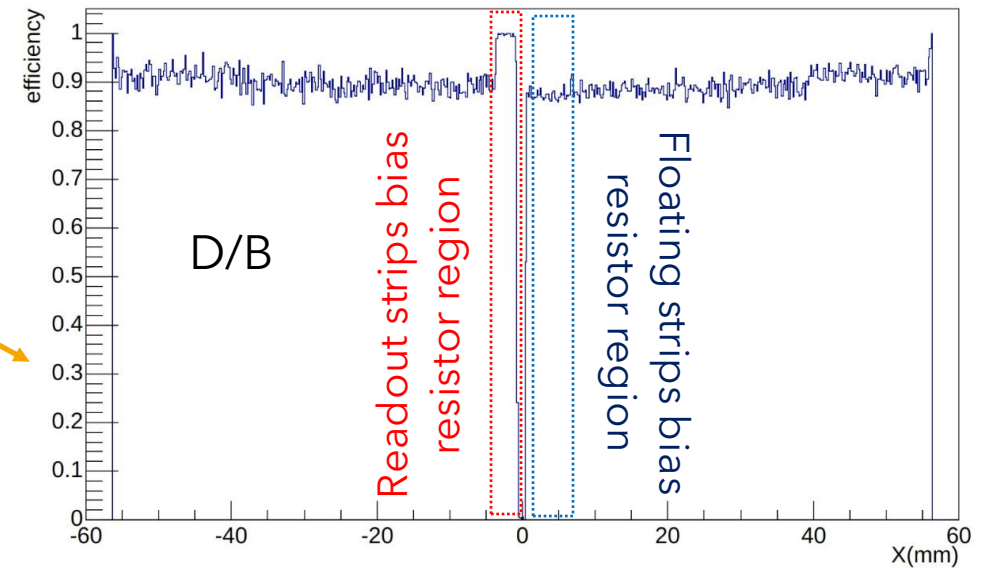
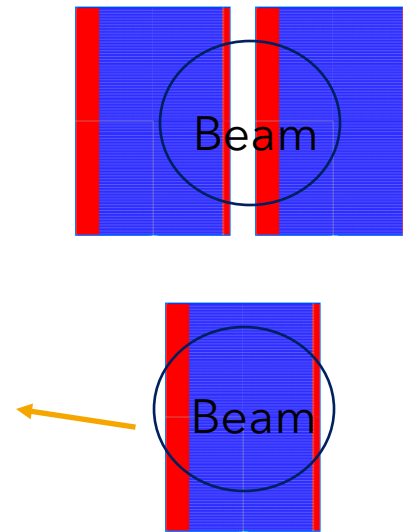
Beam position @ ladder location



Beam position @ ladder & cluster in ladder

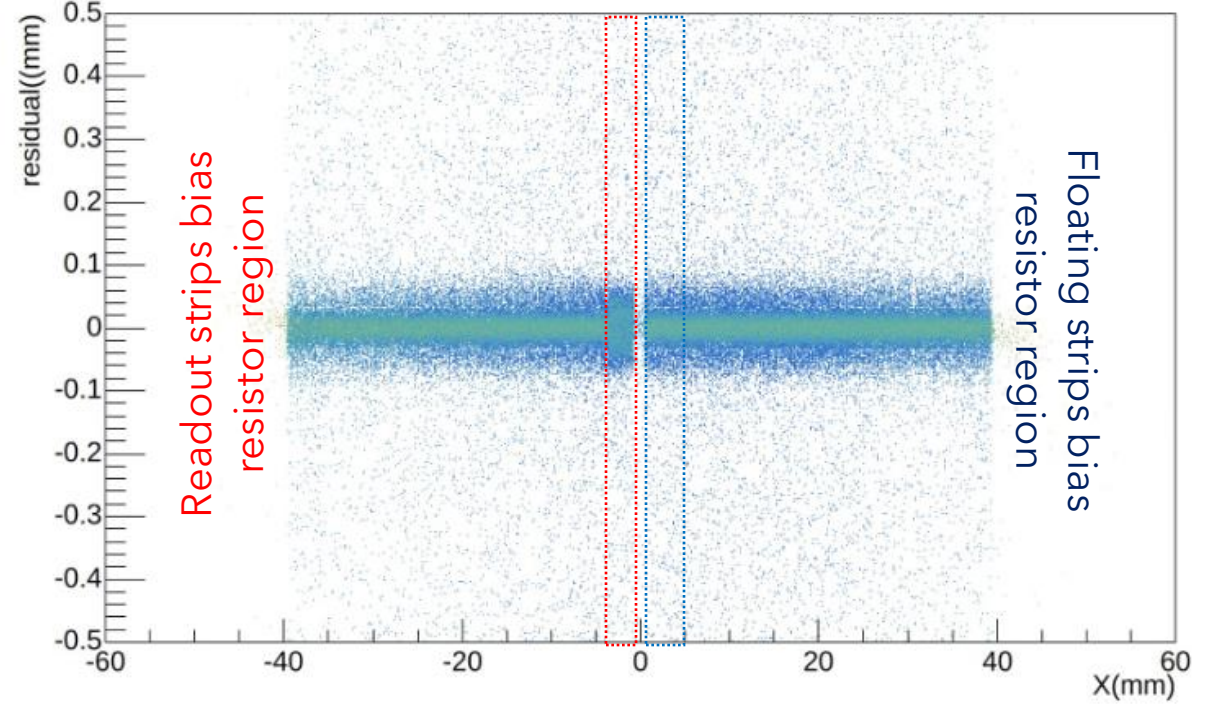
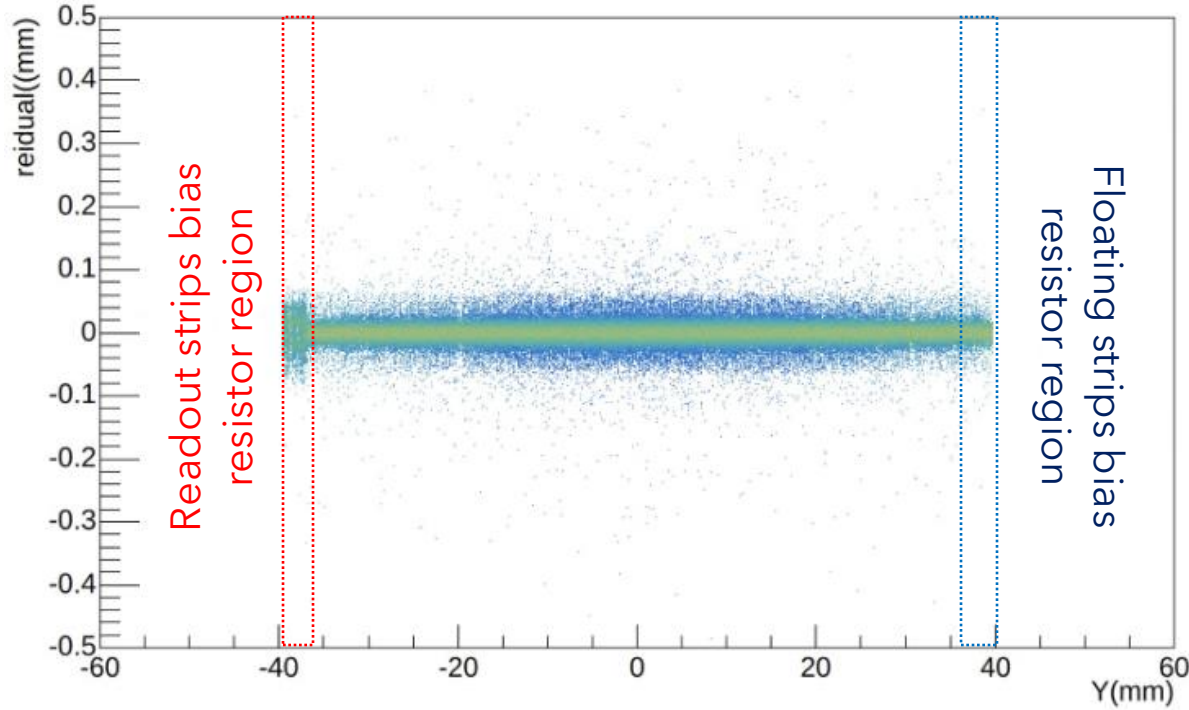


BM: detection efficiency as a function of the coordinate along the strip

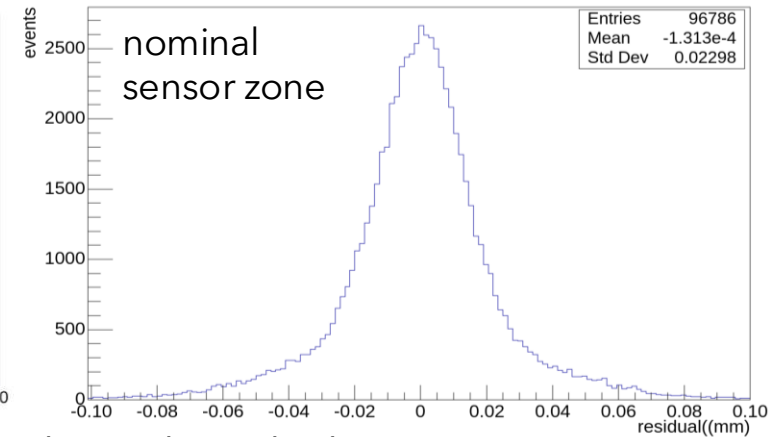
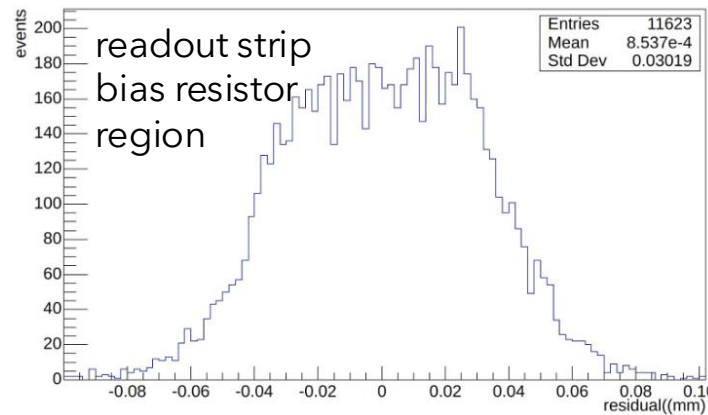


Flight ladder: detection efficiency as a function of the coordinate along the strips

AMS-L0 muon beam test: spatial resolutions in bias resistor regions

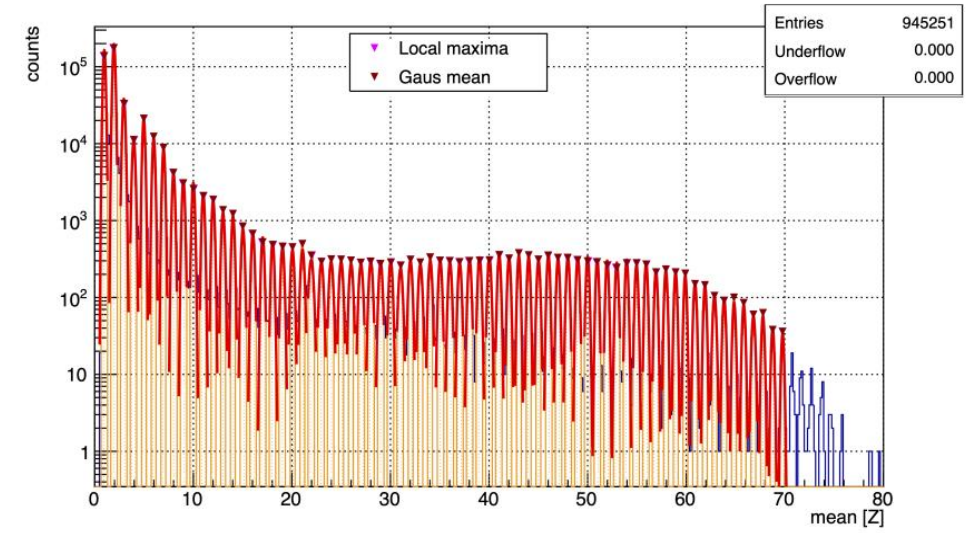
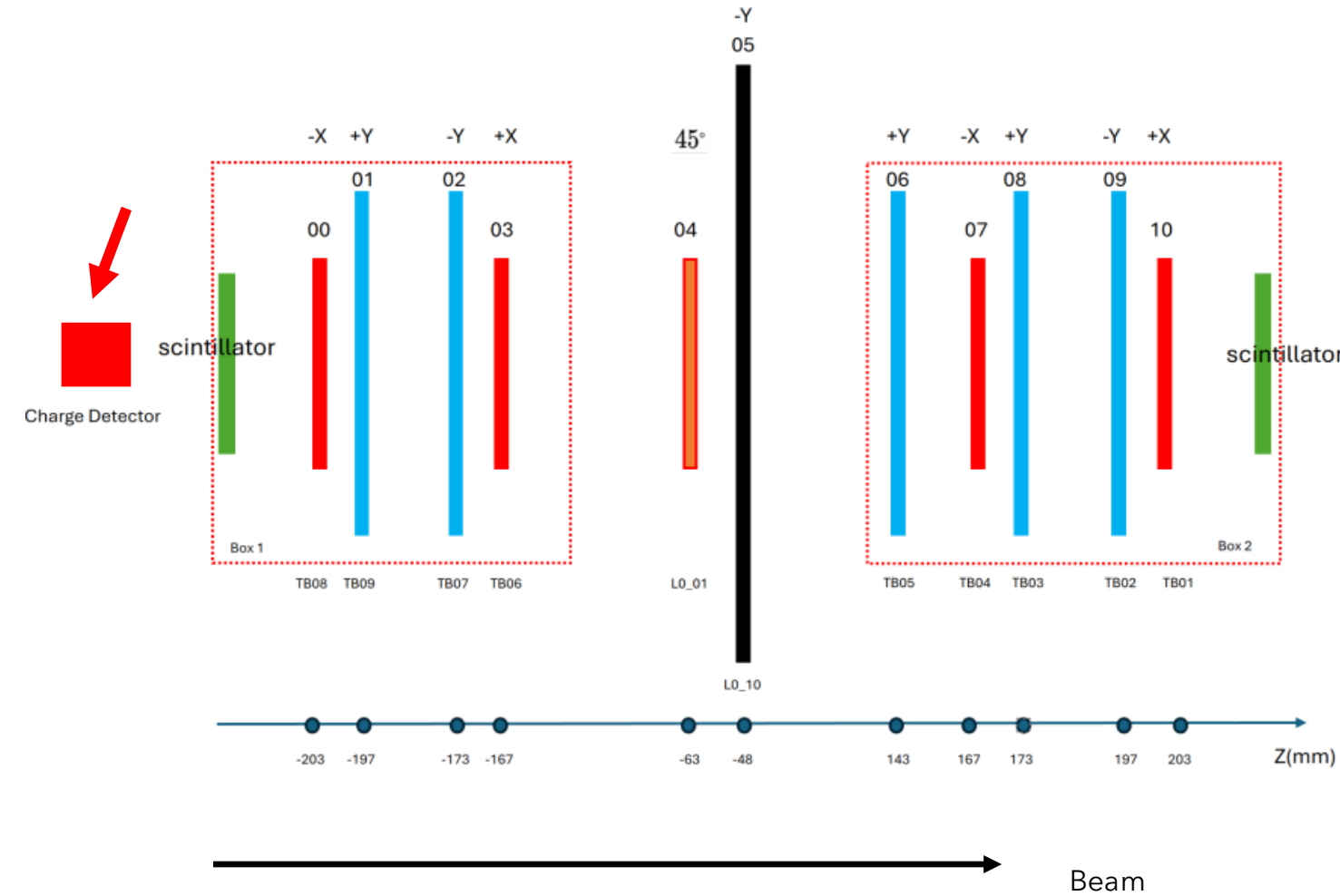


- spatial resolution in readout strip bias resistor region is relatively poor
- spatial resolution in intermediate strip bias resistor region has no significant change



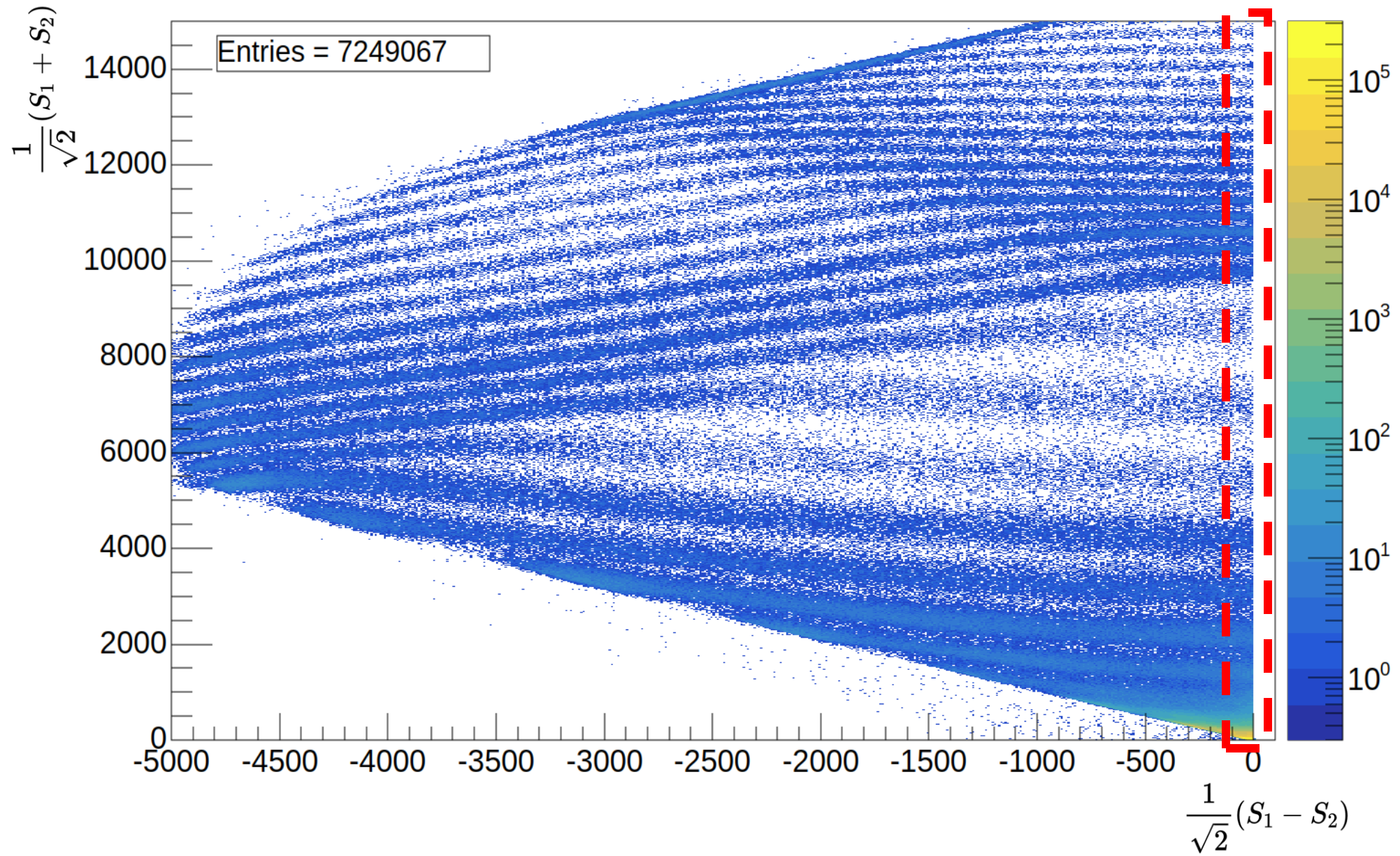
Flight ladder unbiased residuals

AMS-L0 heavy ions beam test(October 2023): setup

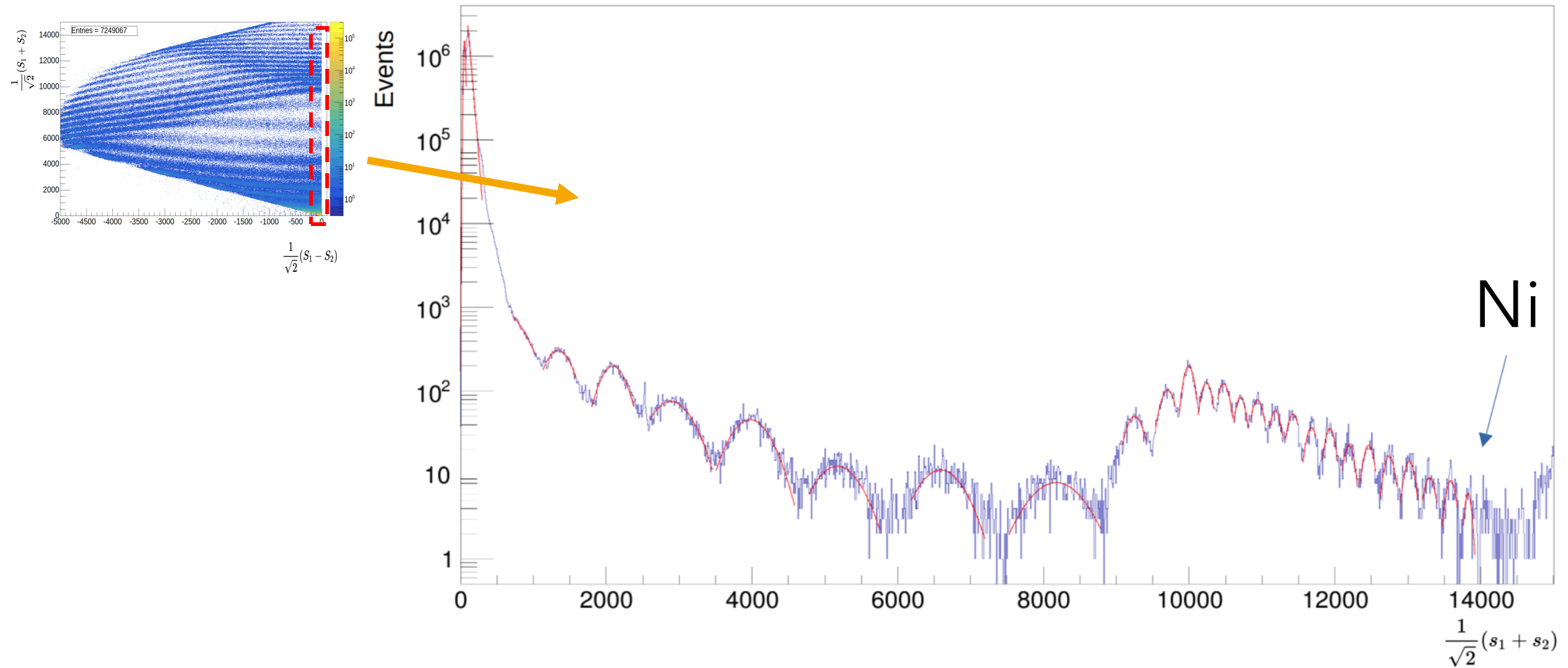


Charge distribution by the Charge Tagger detector

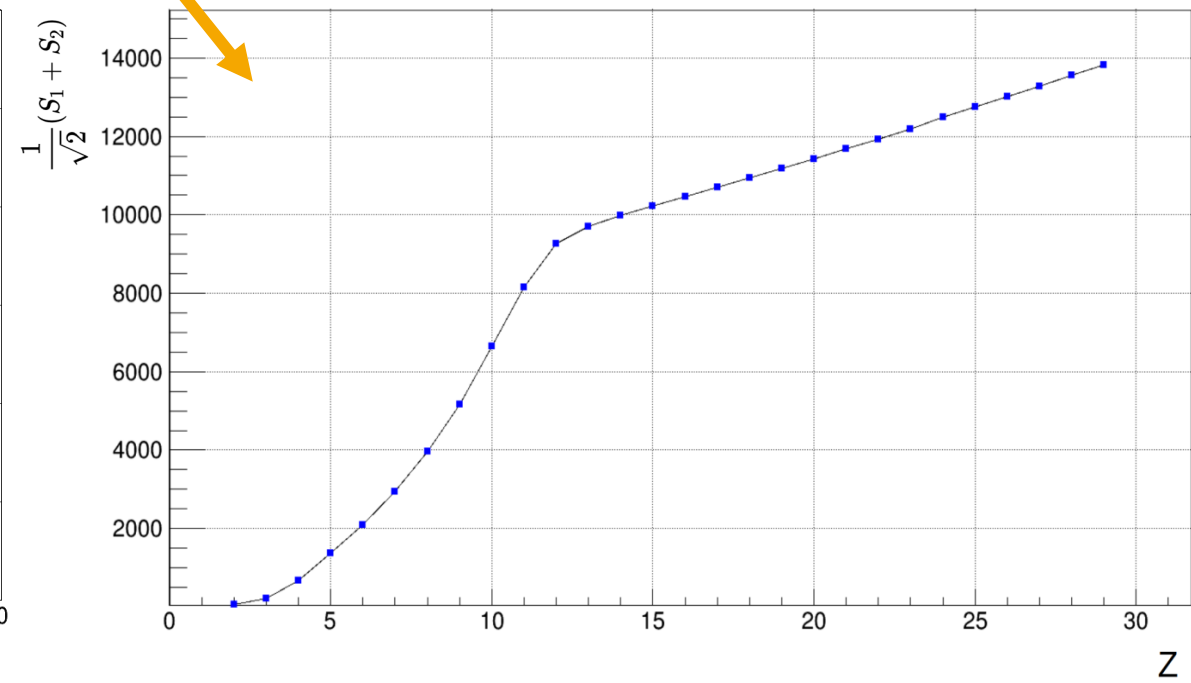
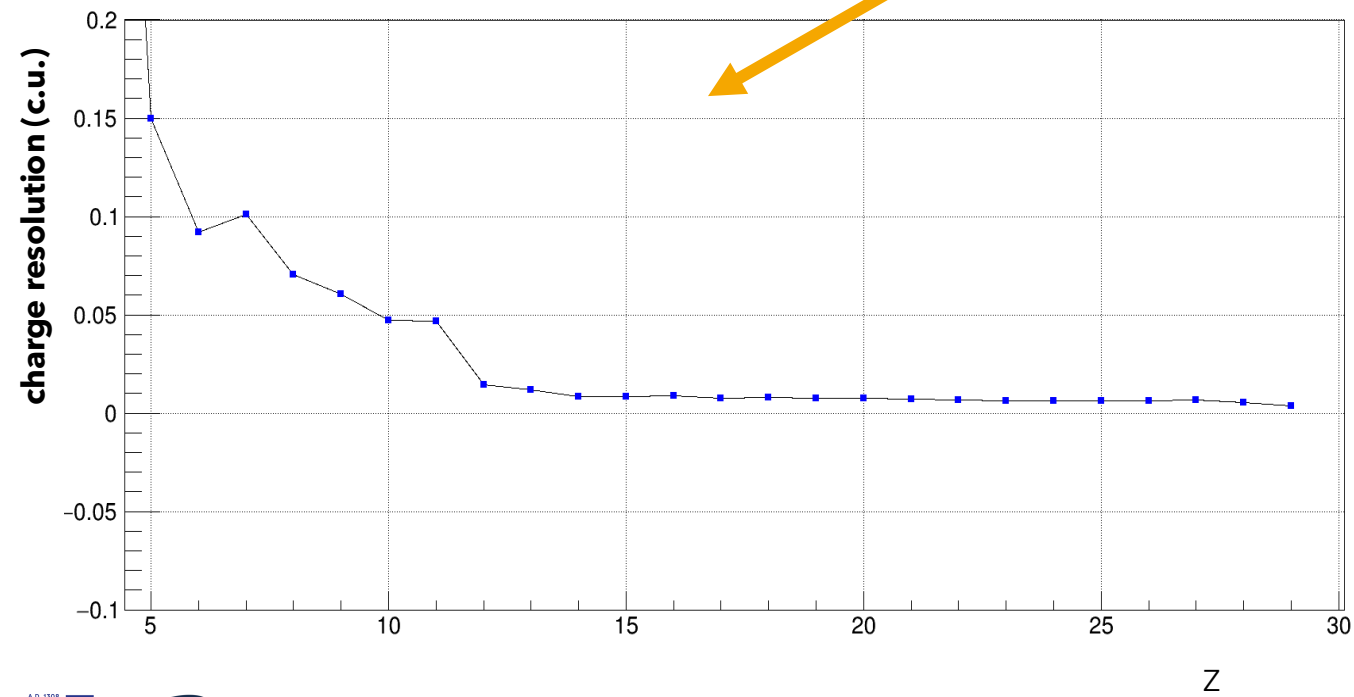
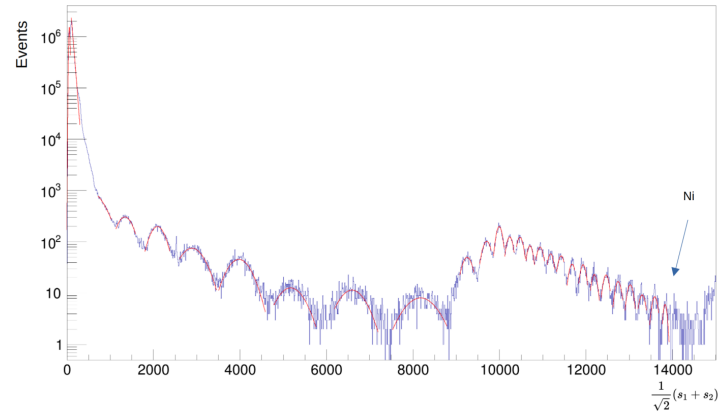
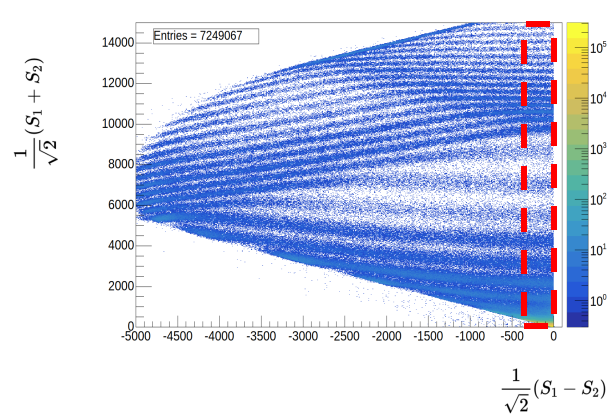
Study of reconstructed charge through S_1 and S_2



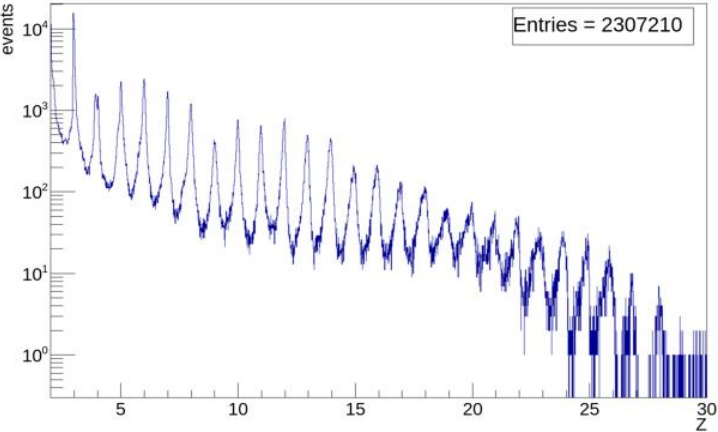
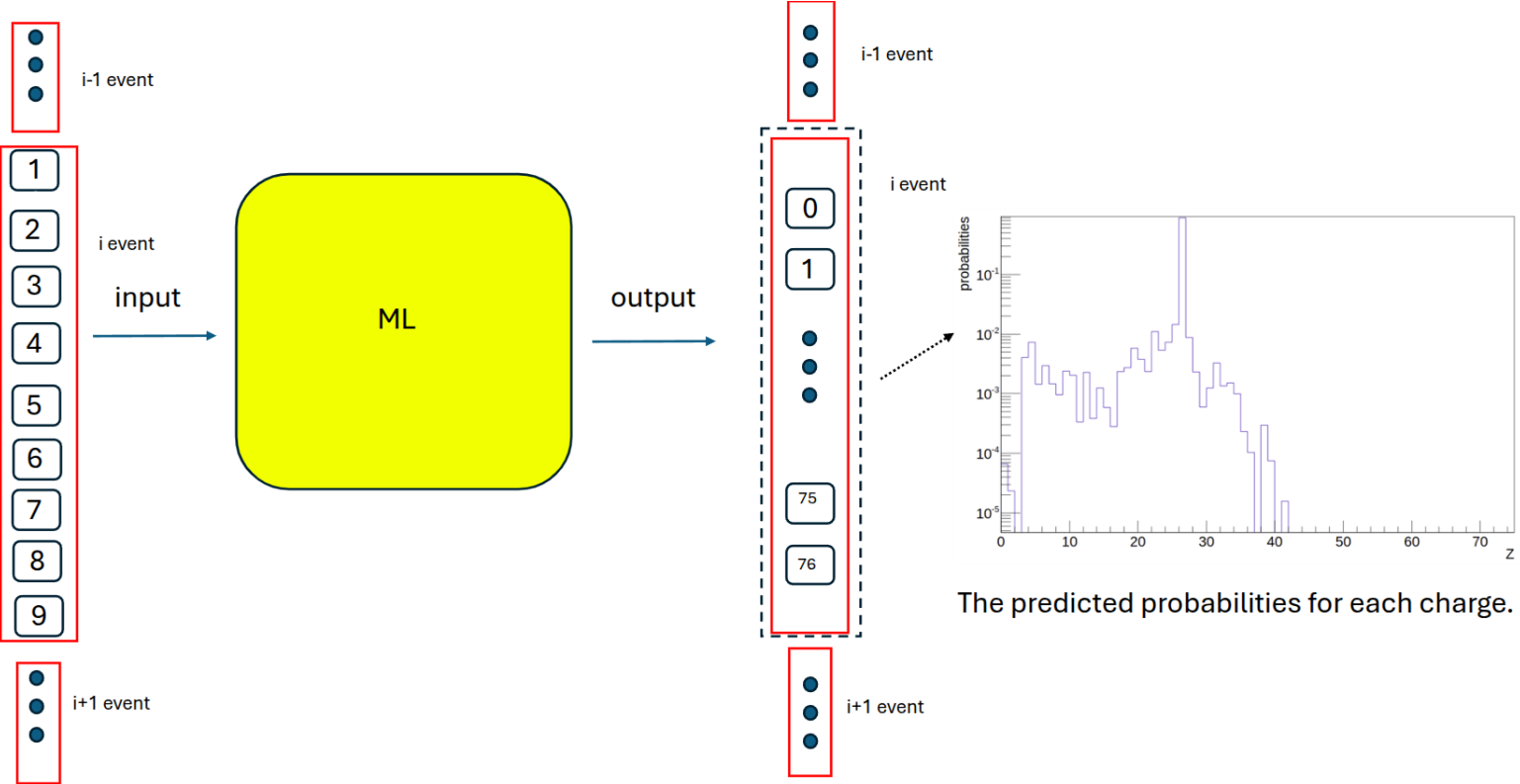
Study of reconstructed charge through $S1$ and $S2$



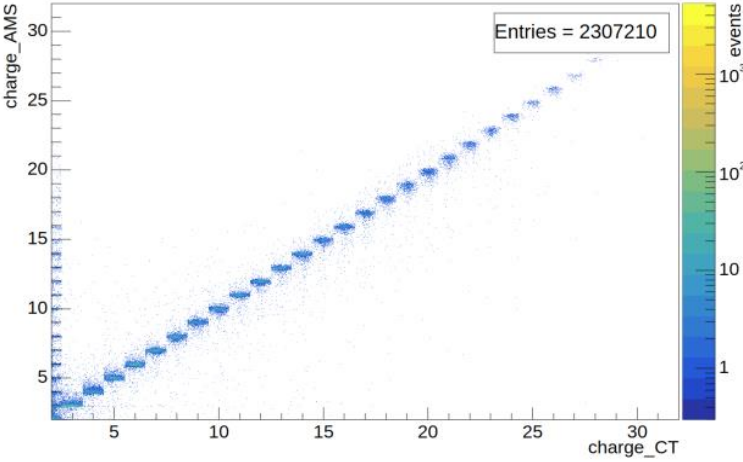
Study of reconstructed charge through S_1 and S_2



Multivariate approach for charge measurement



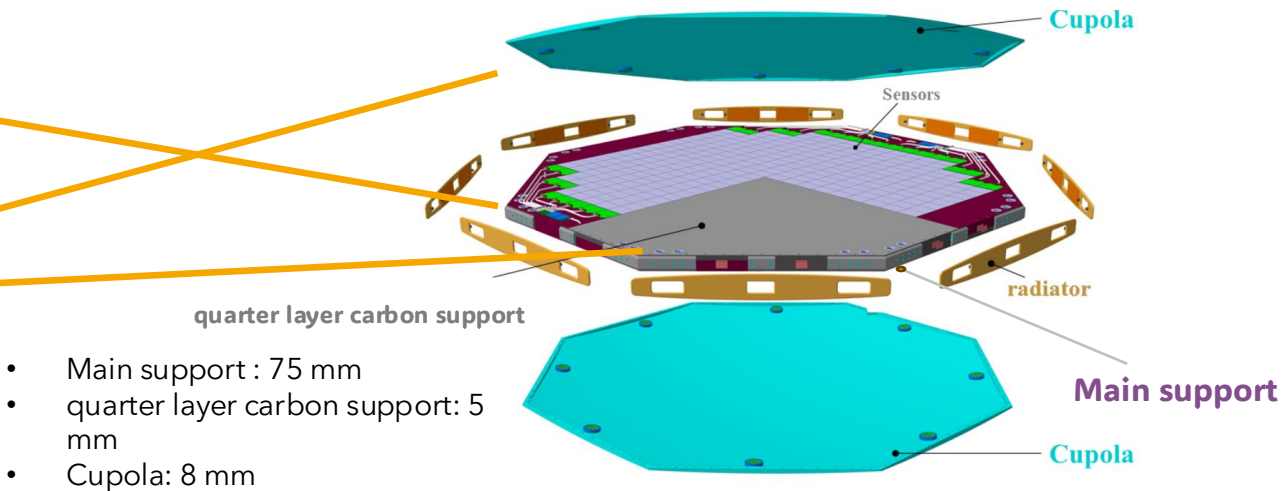
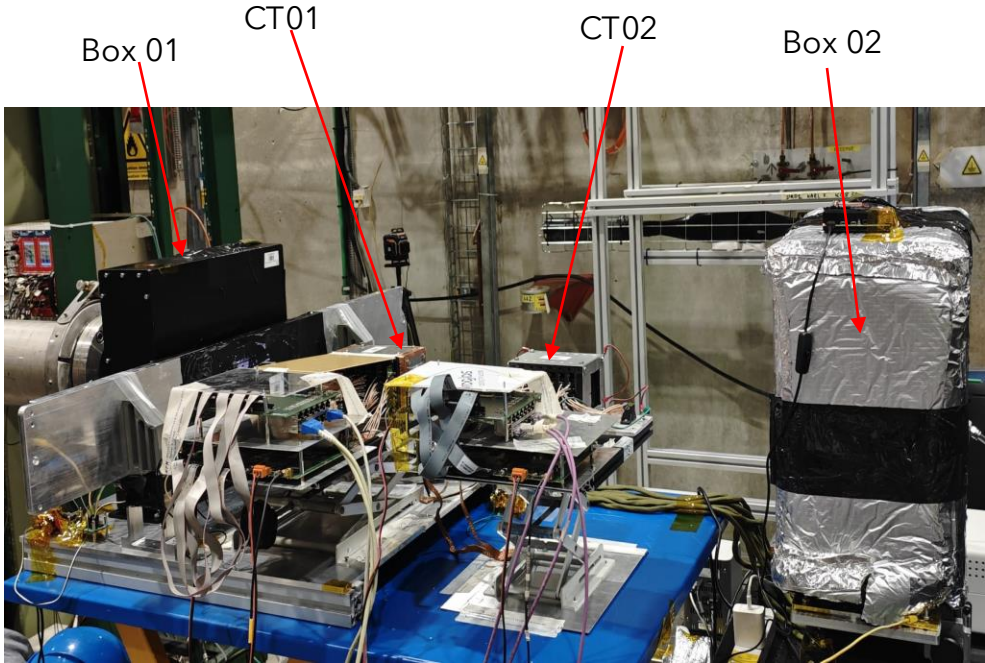
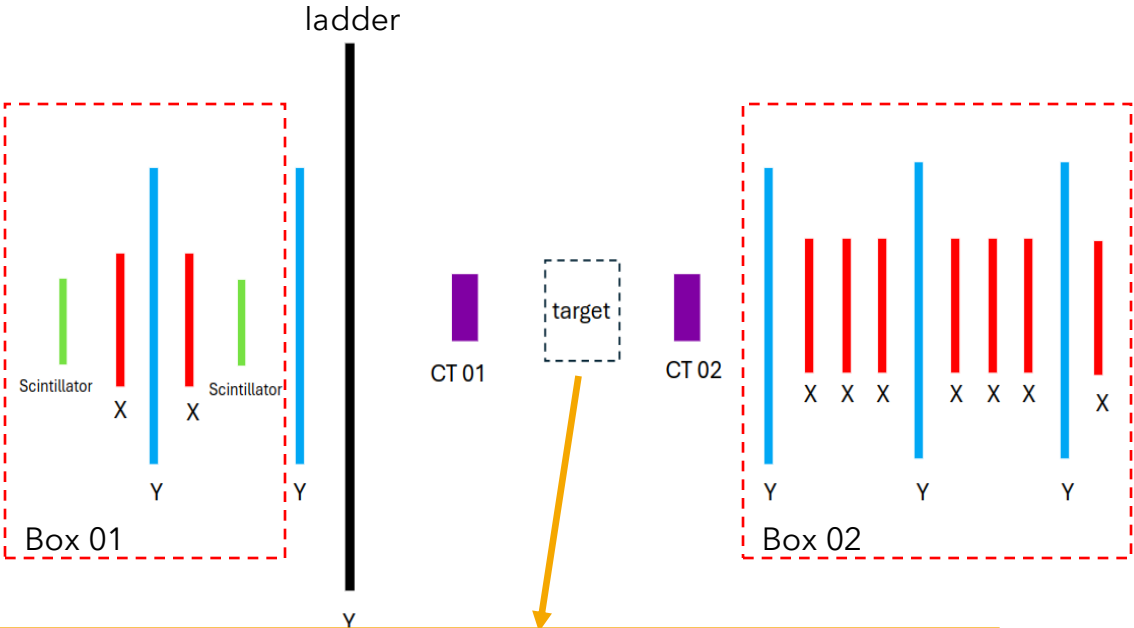
Distribution of the charge measured by the AMS-L0 sensors using a ML approach



Charge measured by the AMS-L0 sensor using a ML approach as a function of the one measured by the CT

- The 9 initial characteristics (*features*) input are: the total signal of the cluster, the signals and positions of the three strongest strips in the cluster, the width and eta of the cluster. The nine feature values come from the cluster with the largest signal in each event
- The 76 output values represent the predicted probabilities for each of the 76 classes (charge)

AMS-L0 heavy ions beam test (November 2024): setup



Summary

A study was carried out on a 10-sensor ladder, focusing on signal-to-noise ratio, detection efficiency, spatial resolution, and charge measurement performances:

- ✓ performances at the single sensor level validate the new sensor design, with no limitations arising from the long bias resistors used;
- ✓ limited deterioration in efficiency and spatial resolution have been measured at the ladder level, despite the strip length being twice that of ladders currently used in AMS-02;